

Historical Data **Since 1968** IEEE International Symposium on Applications of Ferroelectrics (**ISAF**) Conferences

and

Time Curves of the 2008 IEEE IUS for Future Conference Planning

Note: A Microsoft Excel version of these plots for details of the data is accessible at:
https://ewh.ieee.org/conf/ius_2008/z_doc_misc/0_oper_ius2008_plots_isaf.xls

Notes

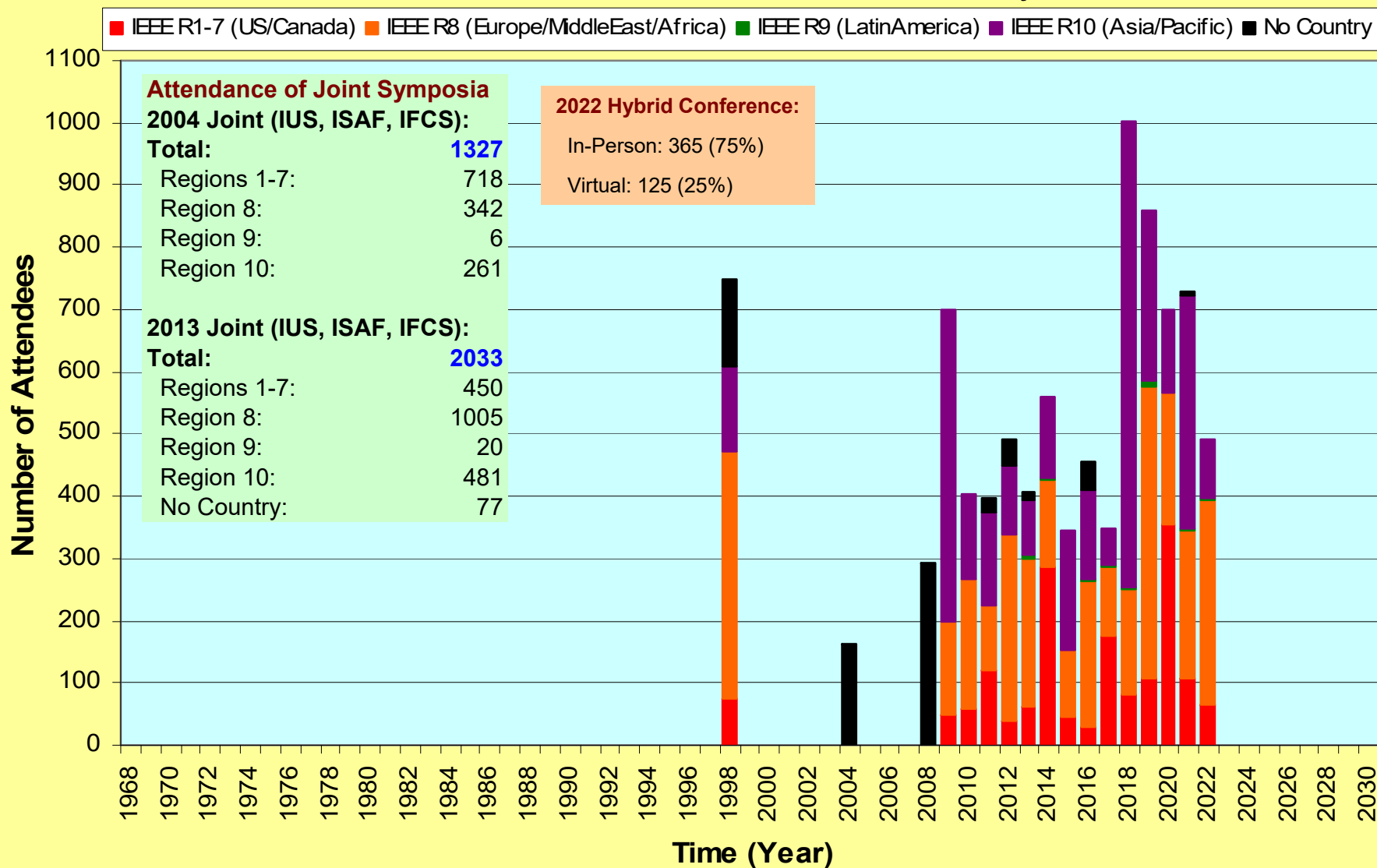
These charts are based on data in the spreadsheet: “**0_oper_ius2008_plots_isaf.xls**”. Comments in the .xls spreadsheet indicate where the data were obtained. The data were collected from various reports and from some individuals. However, they are far from perfect. There are many missing data. There may be inconsistencies such as the number of abstracts accepted is more than submitted or less than the number of conference proceedings papers published in some years. These data are what I have so far and many of the original data might have already been permanently lost.

This underscores the importance that, to collect conference historical data, each conference should fill out the standard data collection form “**00_uffcs_conf_data_collection_fillable.pdf**” soon after the conference while the memory of the conference is still fresh.

Currently, among the three annual UFFC-S conferences, historical data of IEEE IUS are relatively complete and consistent. Thank you all for those who made reports or who provided the data.

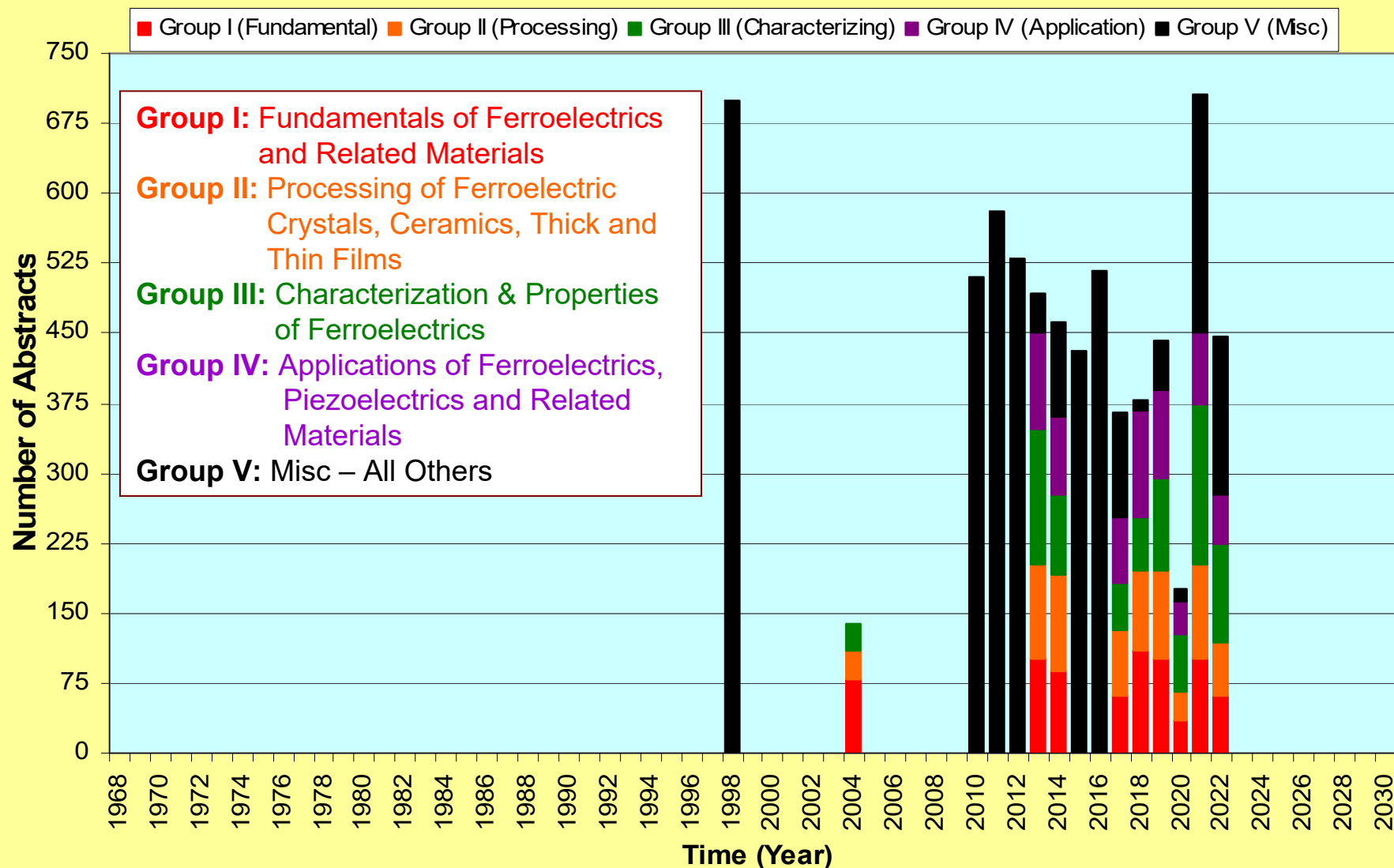
of Attendees of the IEEE International Symposia on Applications of Ferroelectrics (ISAF) by IEEE Regions (Since 1968)

- "0" values mean that data are not available for those years



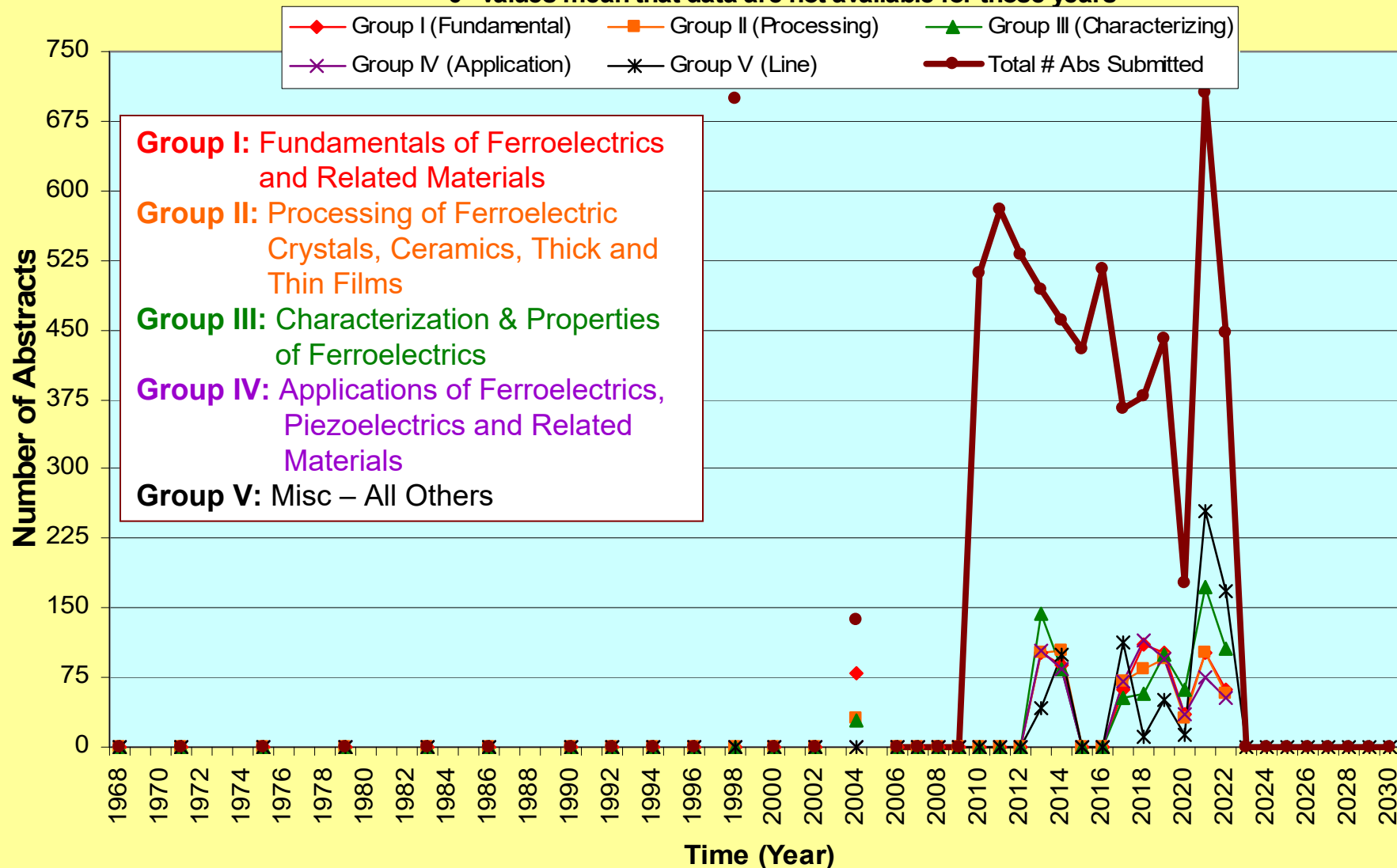
of Abstracts Submitted to the IEEE International Symposia on Applications of Ferroelectrics (ISAF) by Each Group (Since 1968)

- "0" values mean that data are not available for those years; "Solid Bar" means no Group data



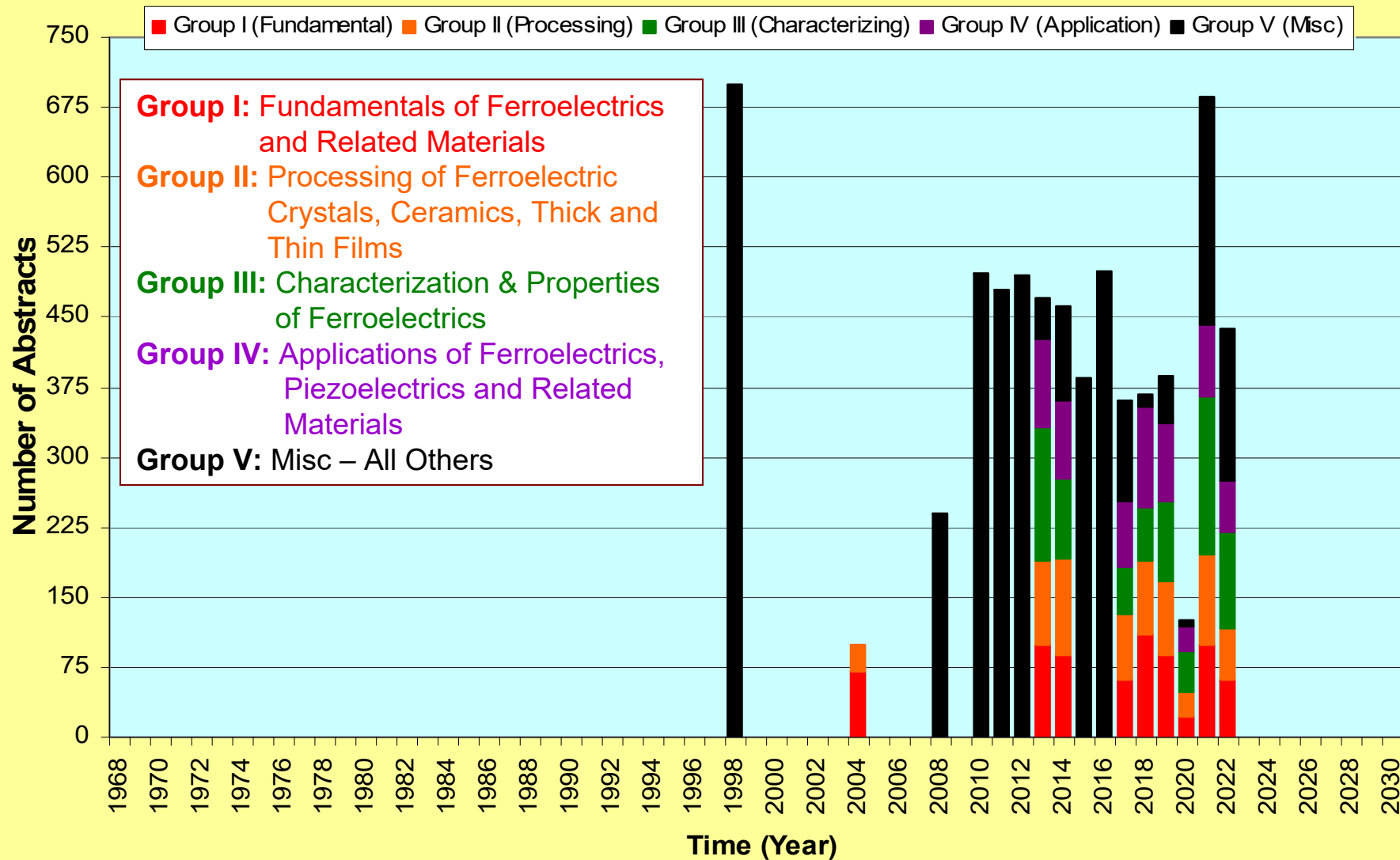
of Abstracts Submitted to the IEEE International Symposia on Applications of Ferroelectrics (ISAF) by Each Group (Since 1968)

- "0" values mean that data are not available for those years



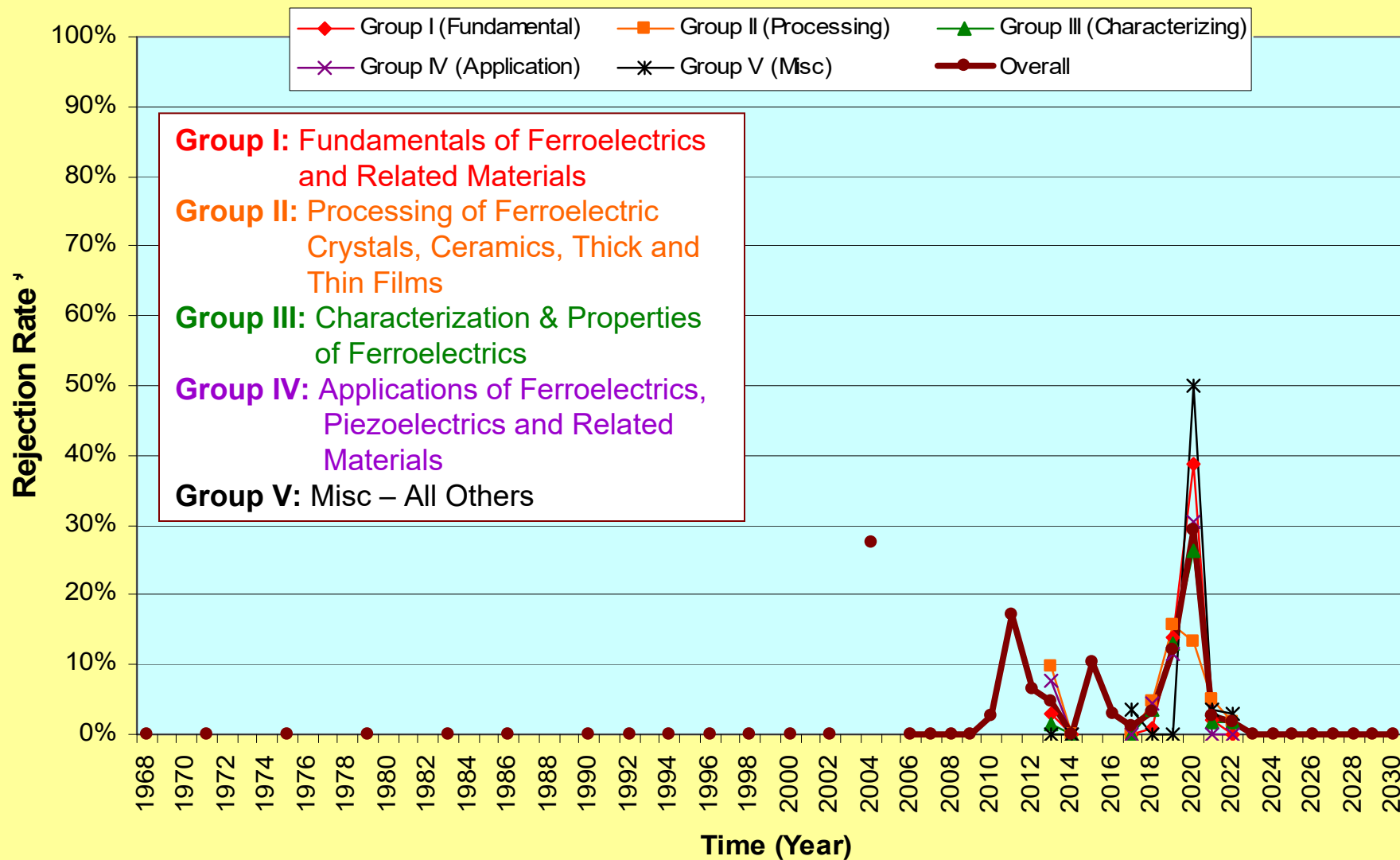
of Abstracts Accepted for the IEEE International Symposia on Applications of Ferroelectrics (ISAF) by Each Group (Since 1968)

- "0" values mean that data are not available for those years; "Solid Bar" means no Group data



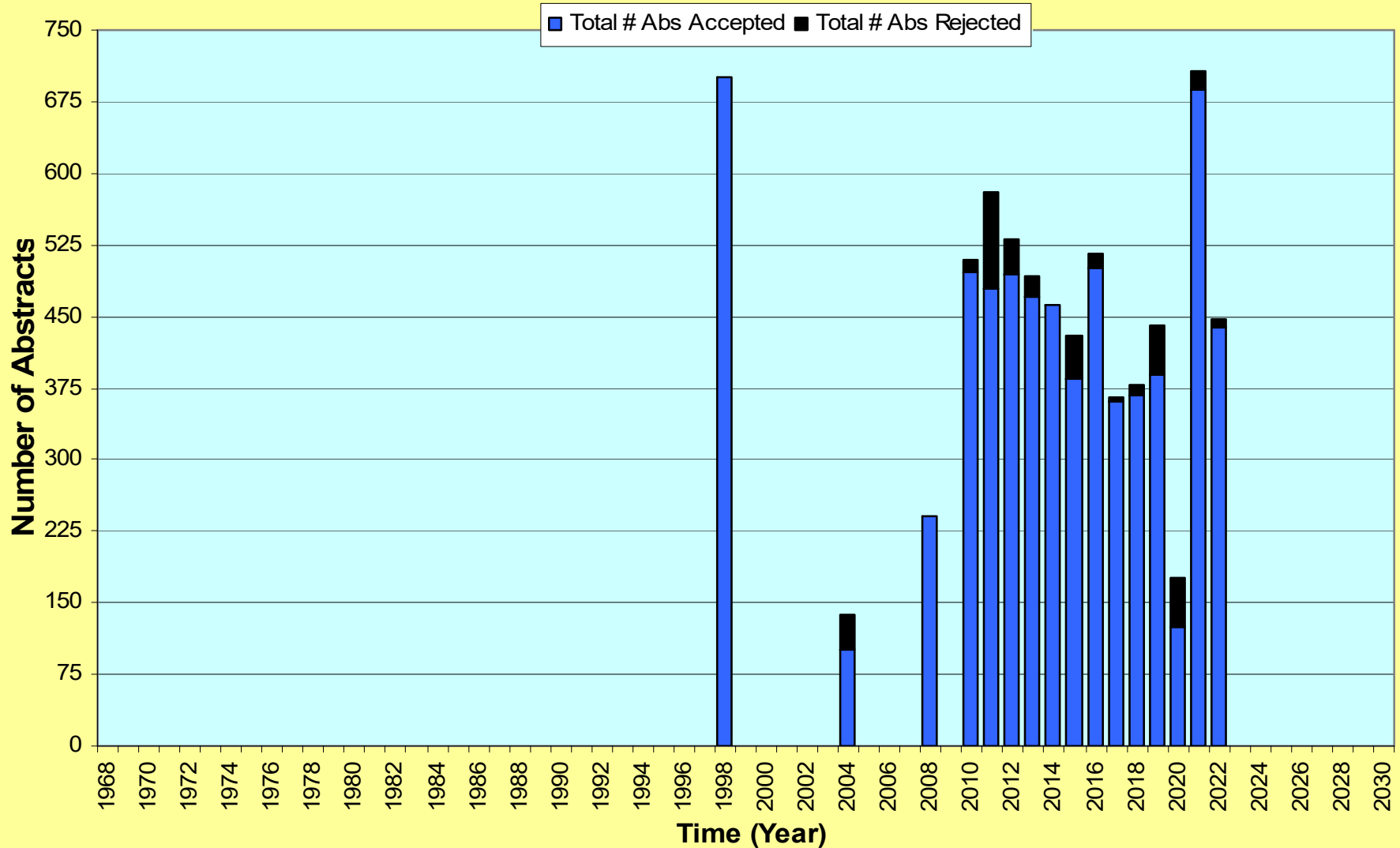
Rejection Rate (%) of the IEEE International Symposia on Applications of Ferroelectrics (ISAF) by Each Group (Since 1968)

- "0" values mean that data are not available for those years



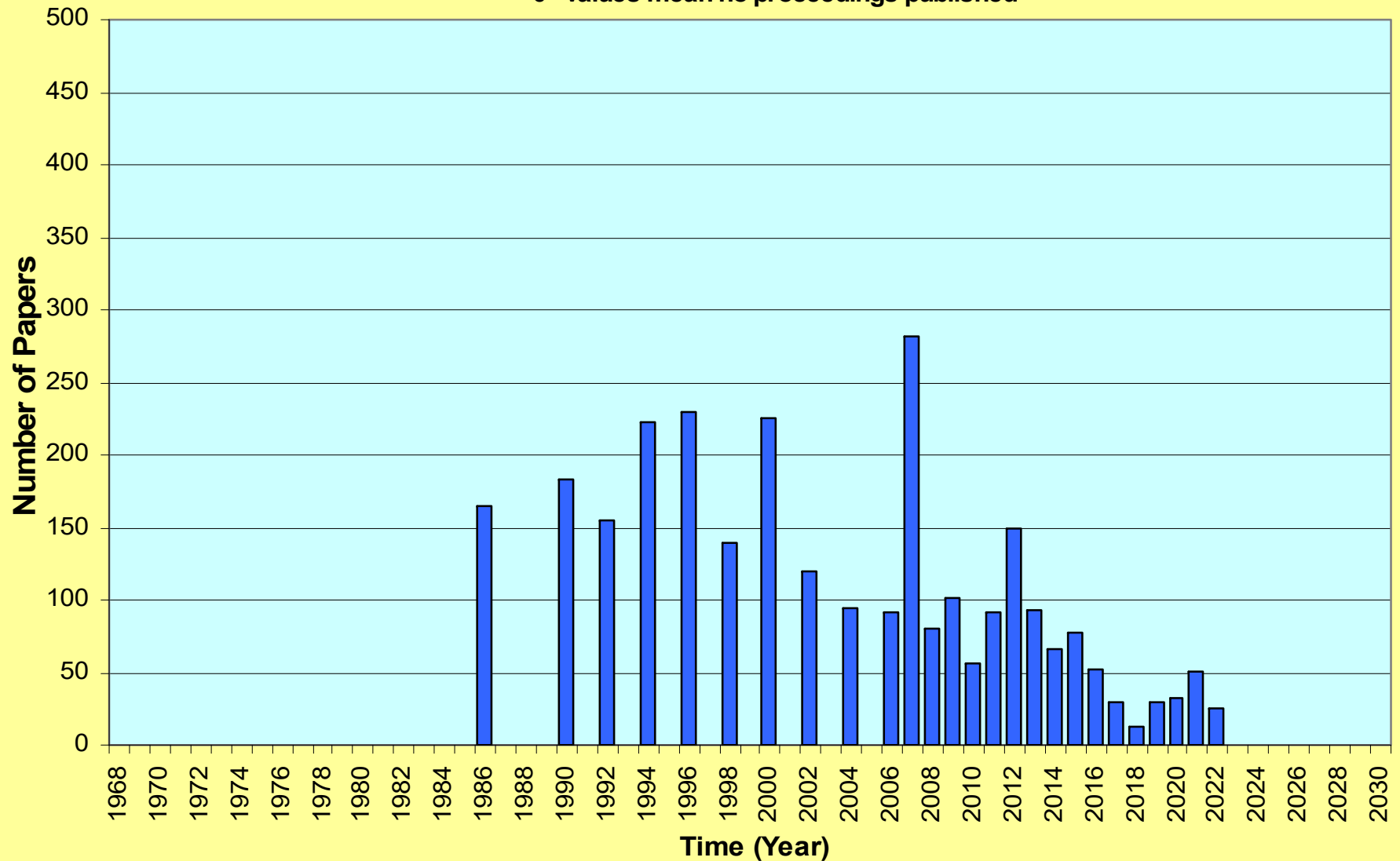
of Abstracts Accepted vs Rejected by the IEEE International Symposia on Applications of Ferroelectrics (ISAF) (Since 1968)

- "0" means that the rejection data are not available for those years

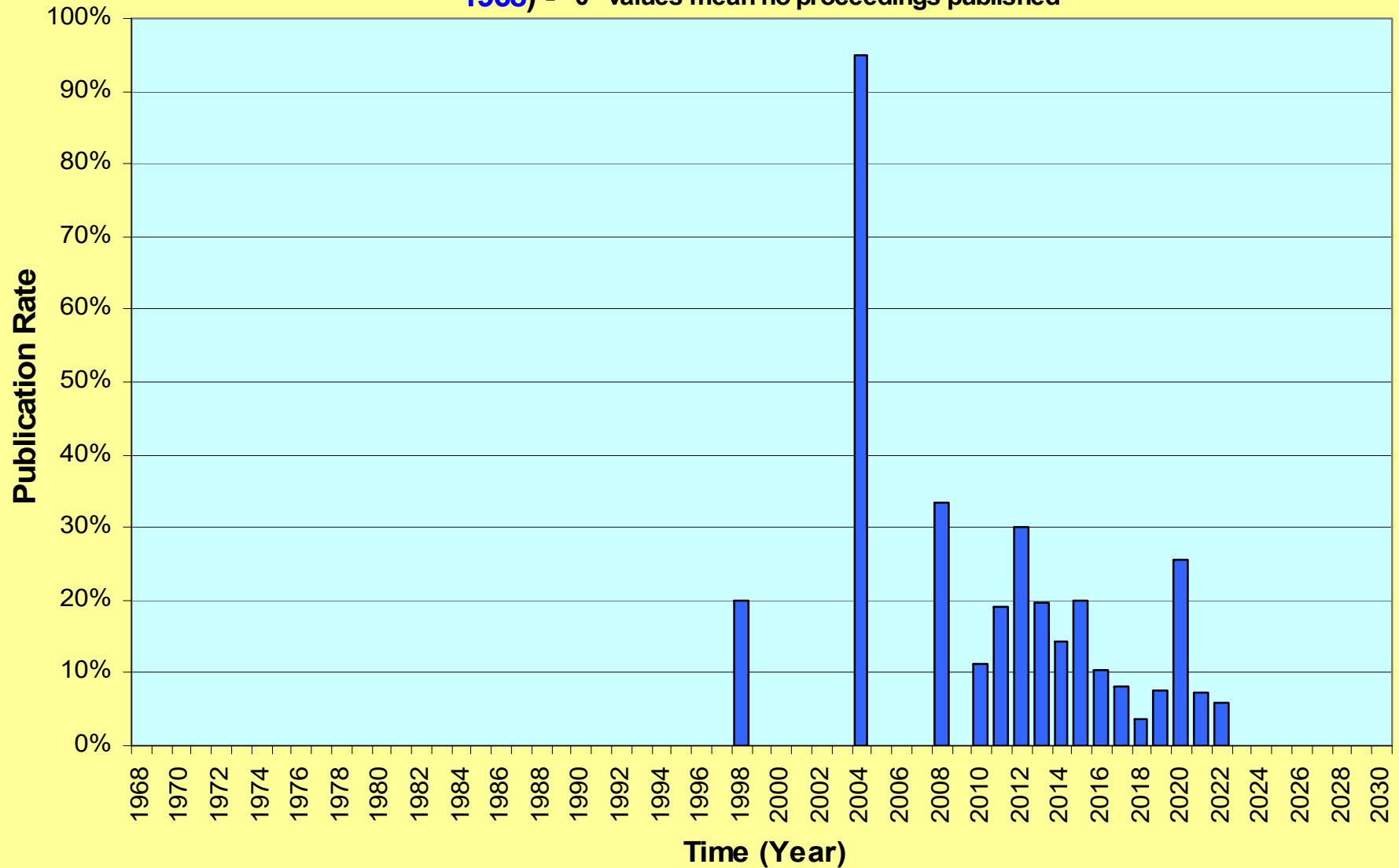


of Papers Published in the Proceedings of the IEEE International Symposia on Applications of Ferroelectrics (ISAF) (Since 1968)

- "0" values mean no proceedings published

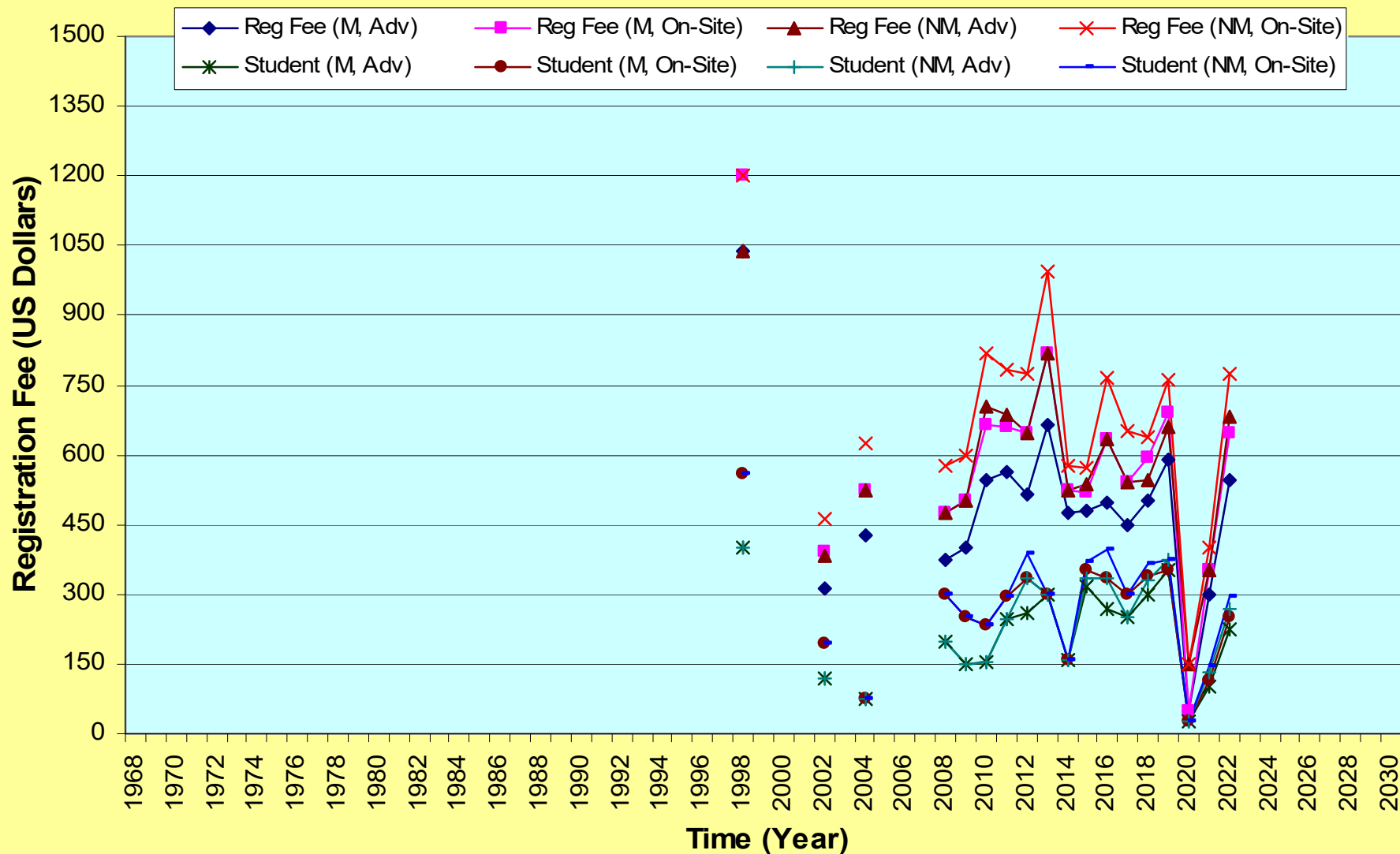


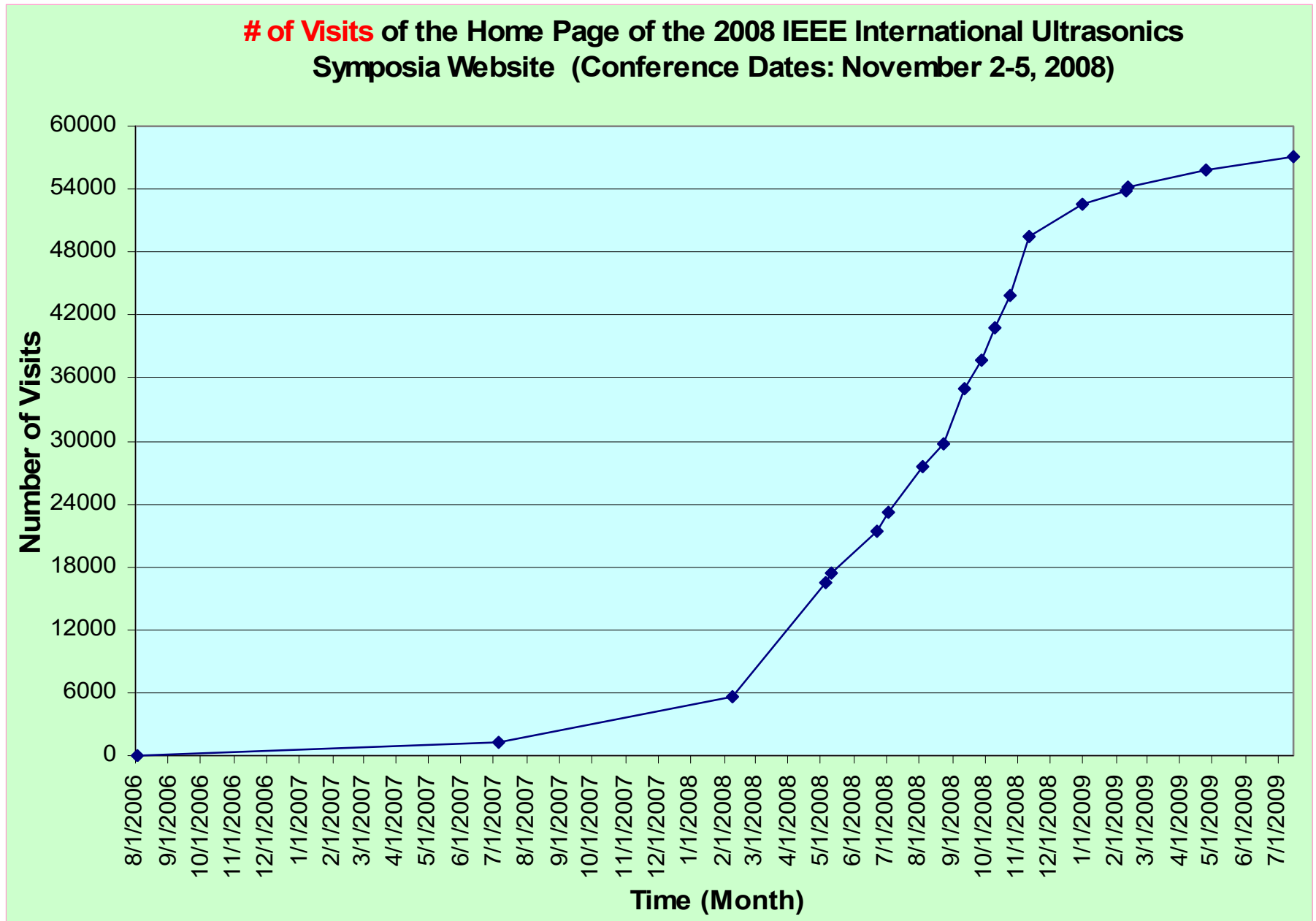
Ratio between the # of Papers Published and # of Accepted Abstracts of the IEEE International Symposia on Applications of Ferroelectrics (ISAF) (Since 1968) - "0" values mean no proceedings published



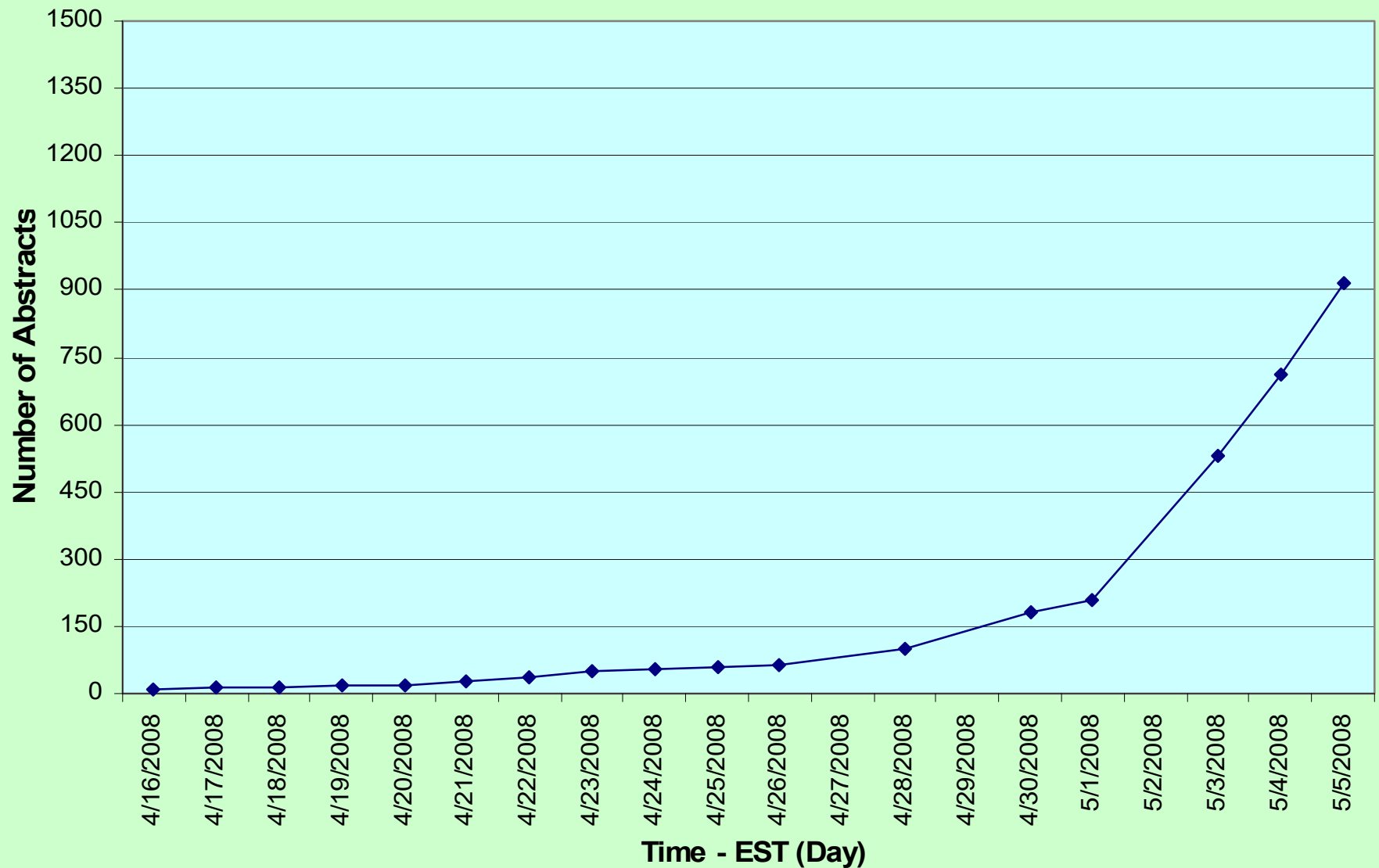
Registration Fees of the IEEE International Symposia on Applications of Ferroelectrics (ISAF) (Since 1968)

- "0" values mean that data are not available for those years

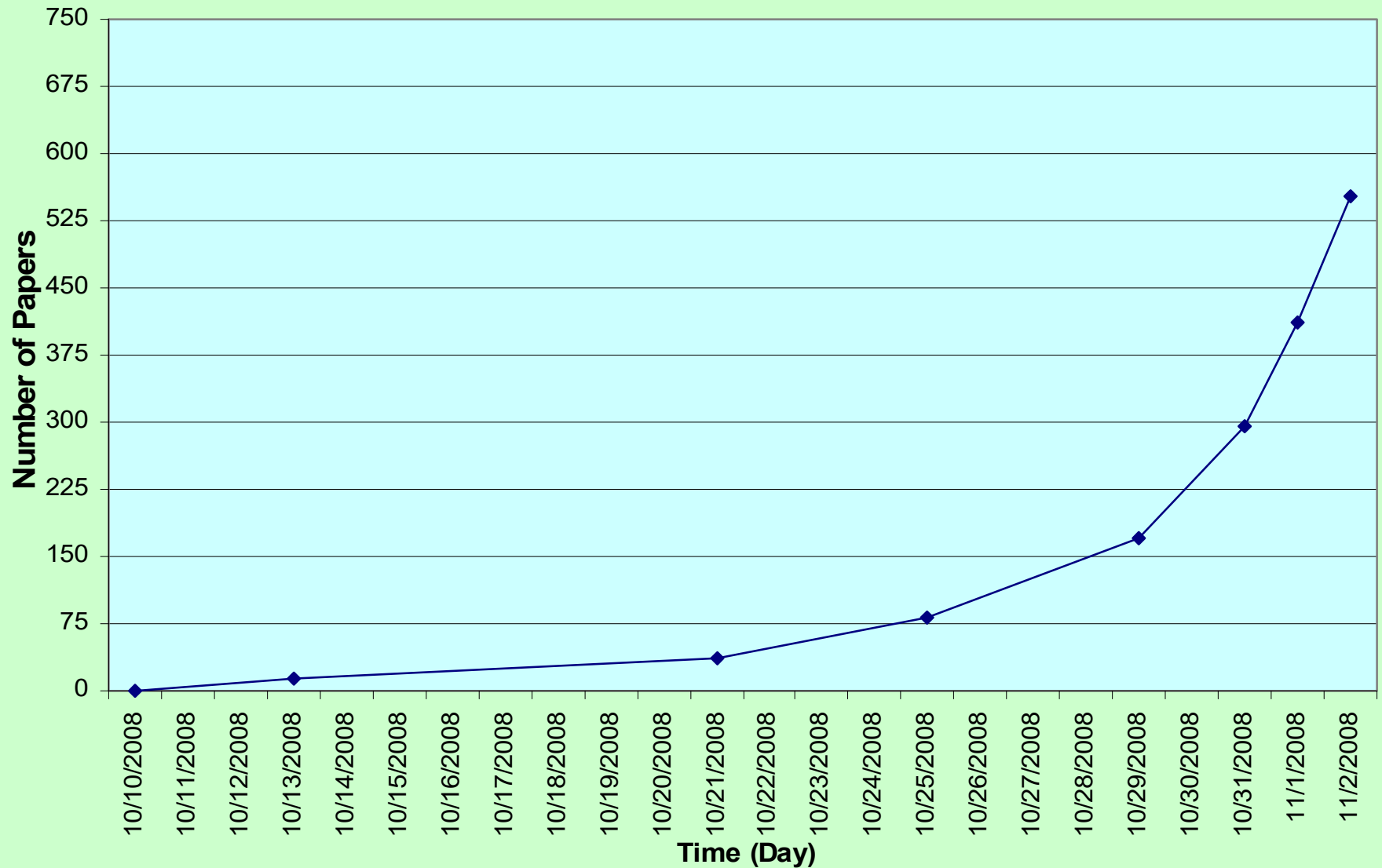


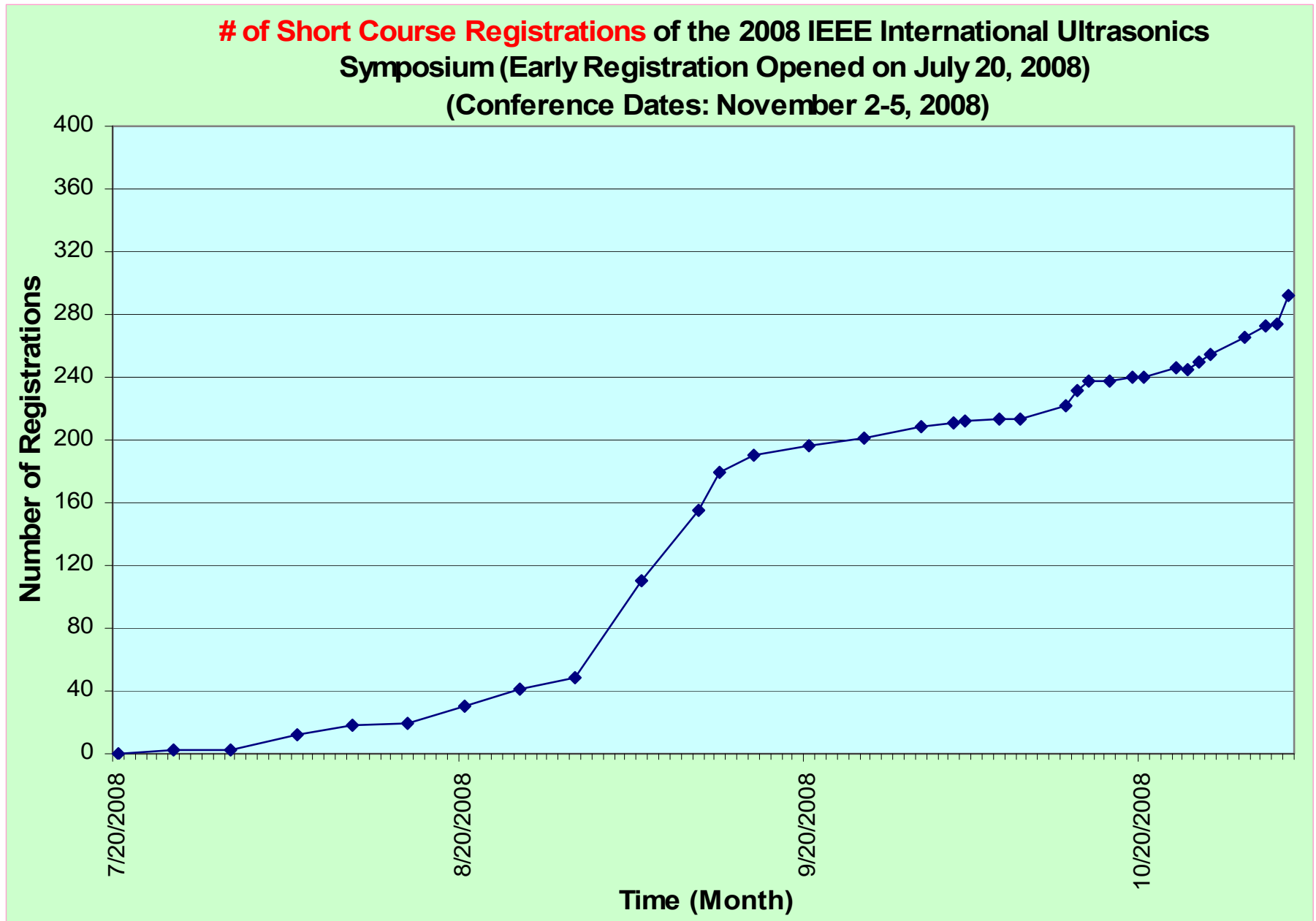


of Abstracts Successfully Submitted to the 2008 IEEE International Ultrasonics Symposium (Submission Deadline: May 4, 2008, PST / May 5, EST)



of Papers Submitted Successfully to the 2008 IEEE International Ultrasonics Symposium (Submission Deadline: Nov. 2, 2008, Beijing Time)





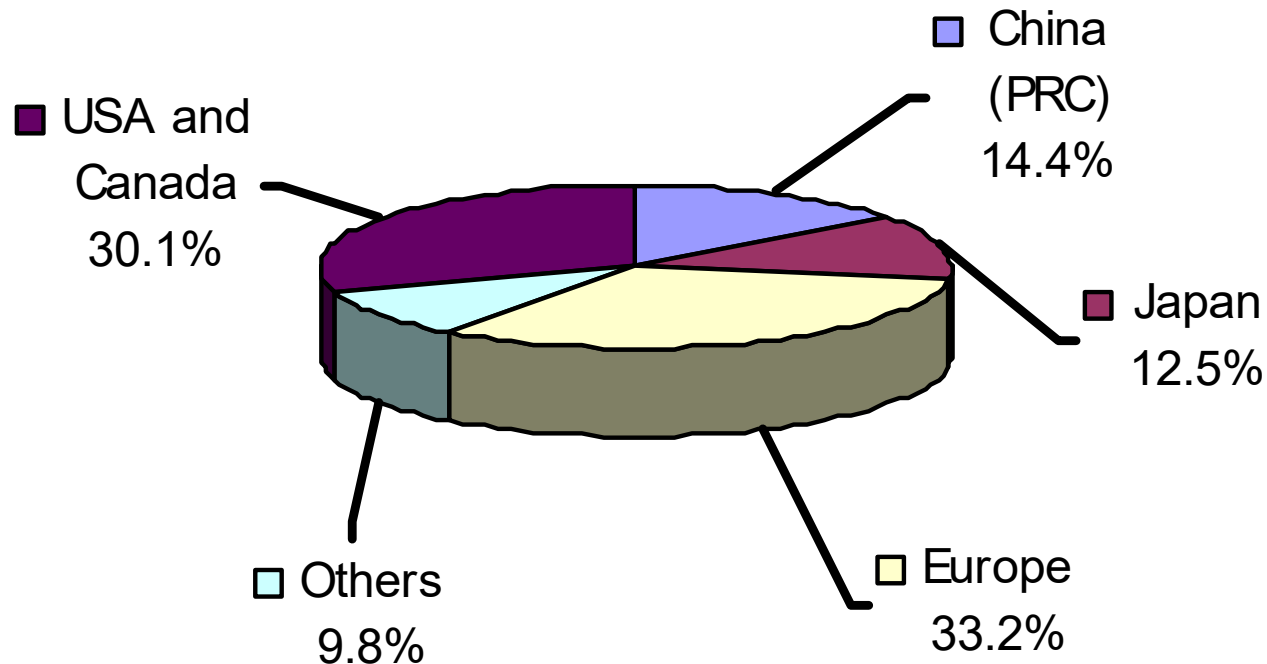
of Conference Registrations of the 2008 IEEE International Ultrasonics Symposium (Conference Dates: November 2-5, 2008)



1. Abstracts (674) accepted from 37 countries

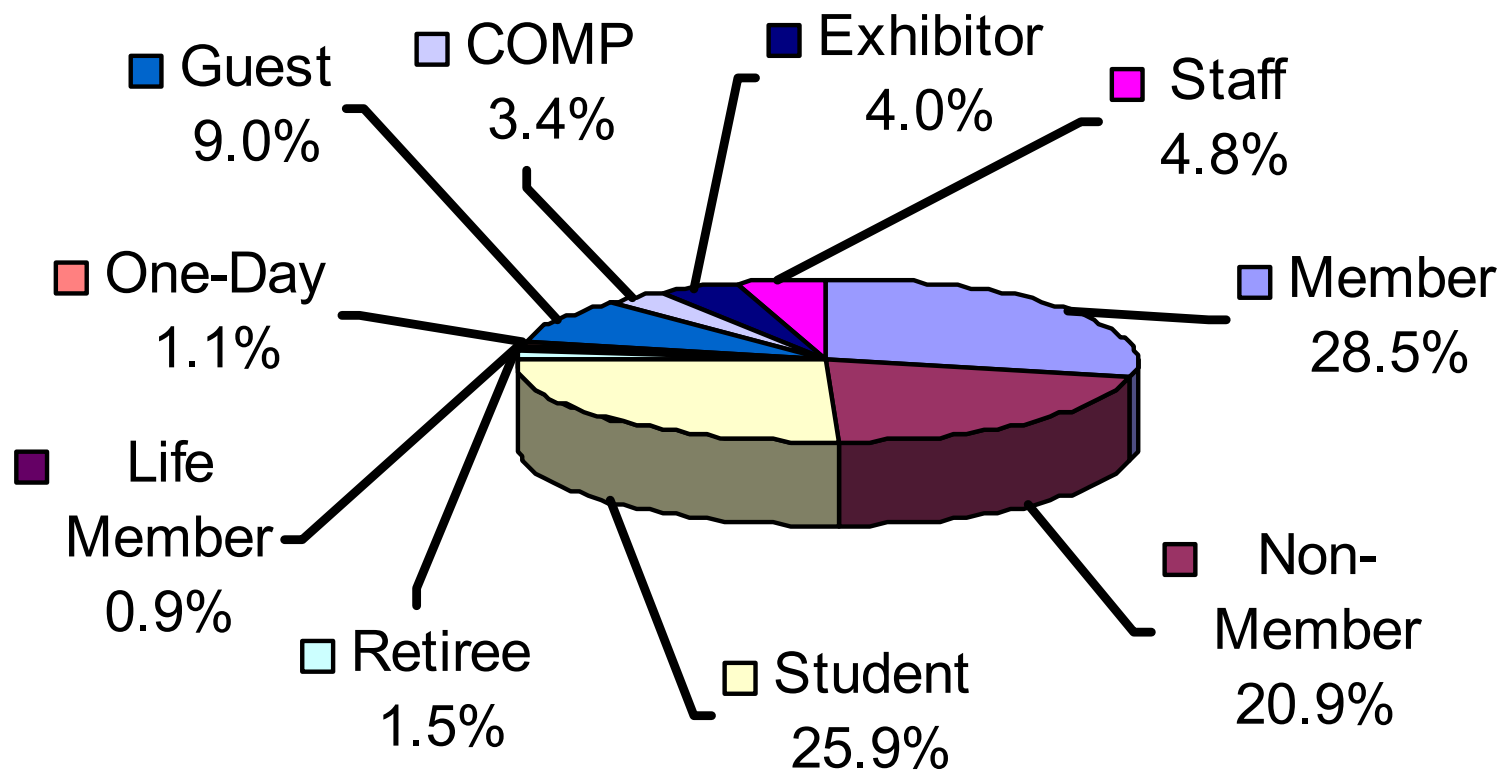
Accepted Abstract by Country in the Technical Program (Total 674)

(2008 IEEE IUS, Beijing, China, November 2-5, 2008)



2. Attendees (1023) in 10 categories

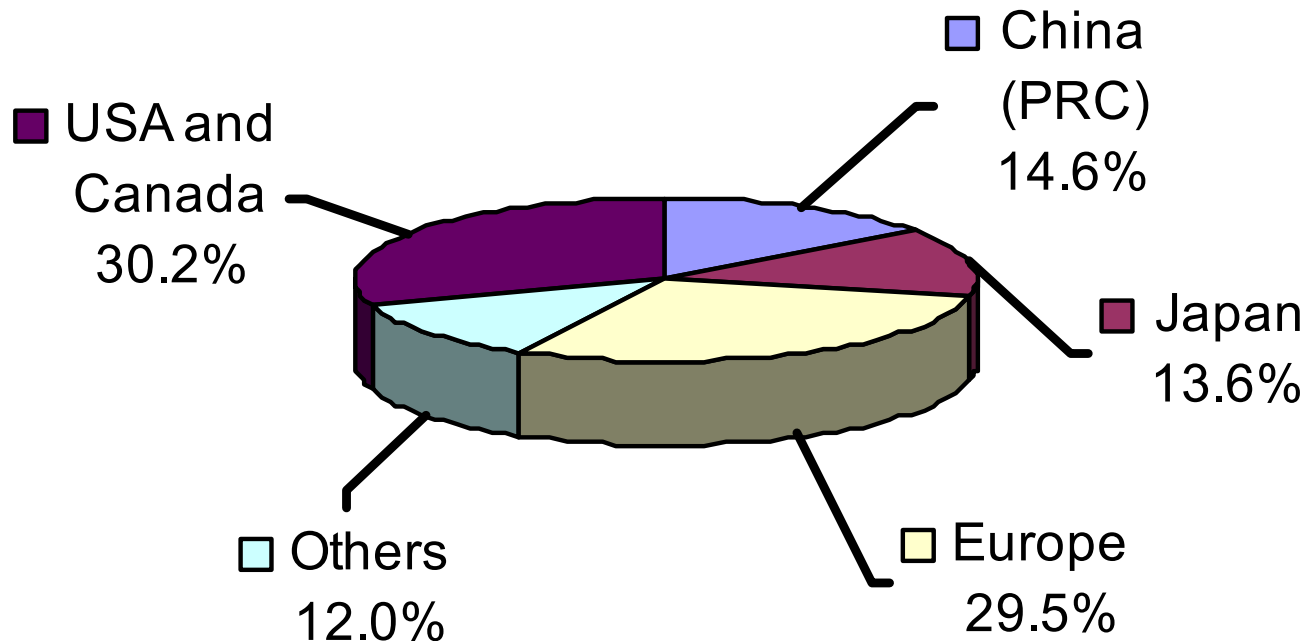
Registration Types (Total **1023** Attendees)
(2008 IEEE IUS, Beijing, China, November 2-5, 2008)



Note: Most “COMP” registrants are invited speakers

3. Conference Registration from 32 countries

Registration Distribution by Country (Excluding Staff and Exhibitors)
(2008 IEEE IUS, Beijing, China, November 2-5, 2008)

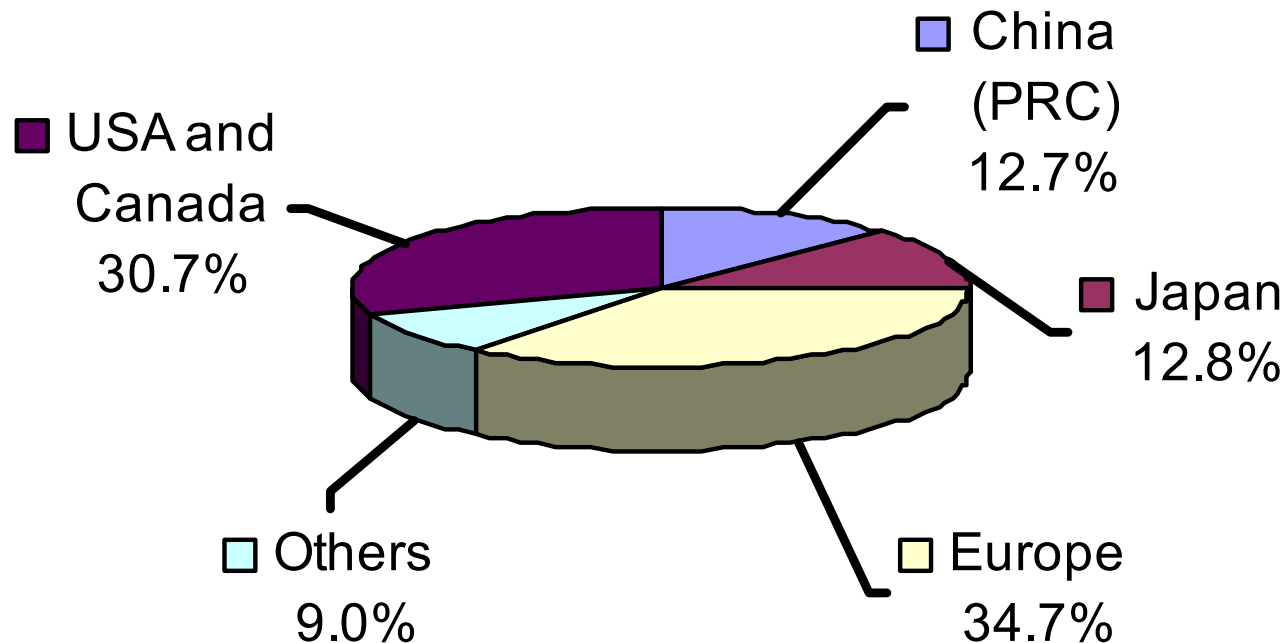


Note: The country counts of all charts do not include those of coauthors

4. Papers (553) published from 32 countries

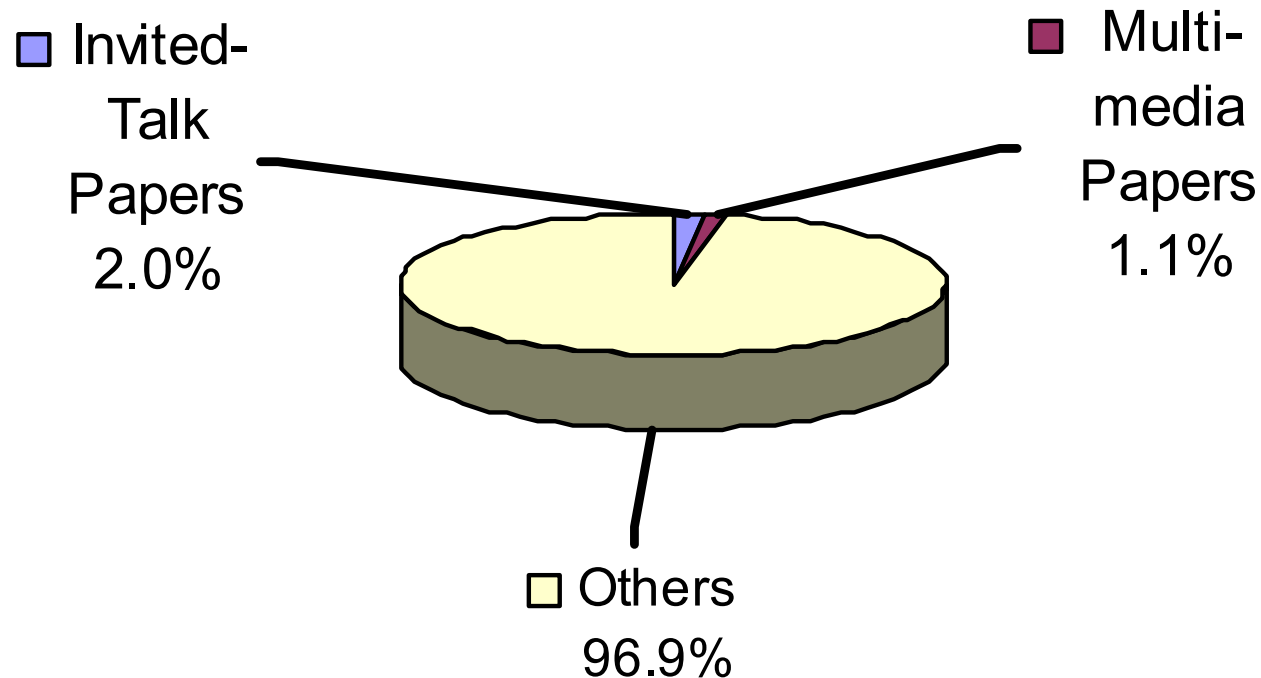
Number of Papers in Proceedings by Country (Total 553 Papers)

(2008 IEEE IUS, Beijing, China, November 2-5, 2008)



5. Papers (553) published in 3 categories

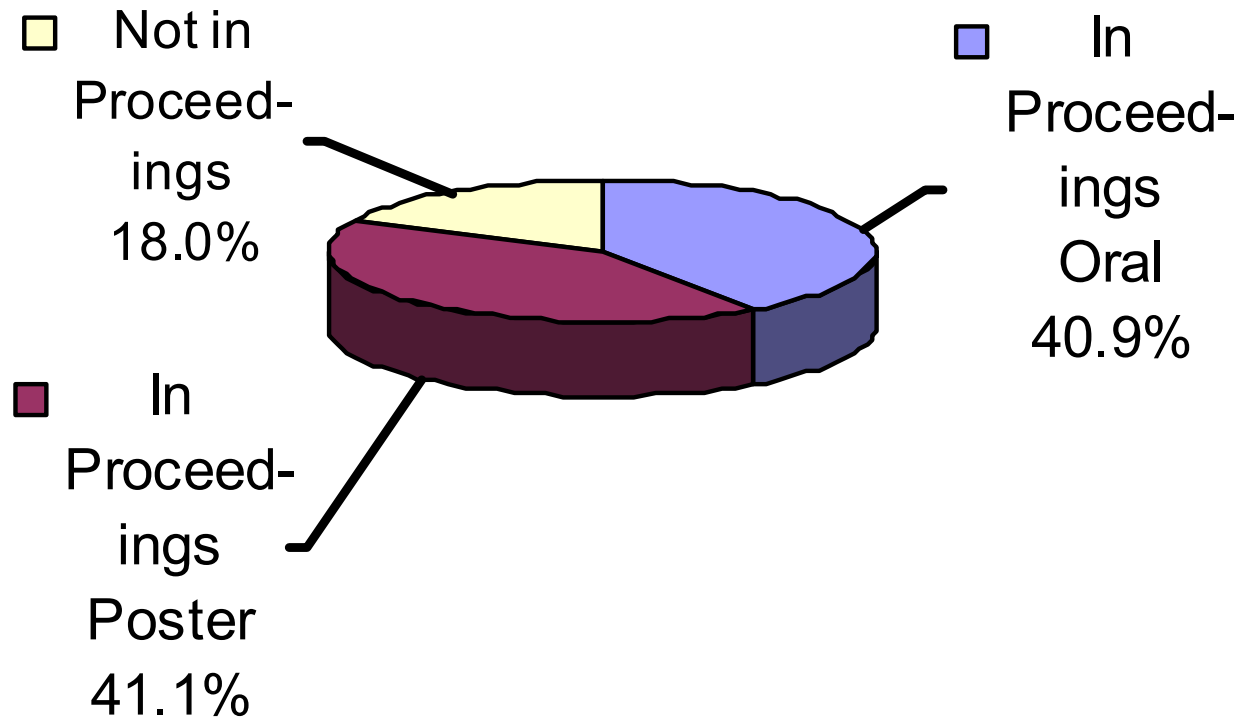
Paper Types in Proceedings (Total 553 Papers)
(2008 IEEE IUS, Beijing, China, November 2-5, 2008)



6. Papers (553) published from accepted abstracts (674)

Abstracts Statistics for Proceedings (Total 674 Abstracts)

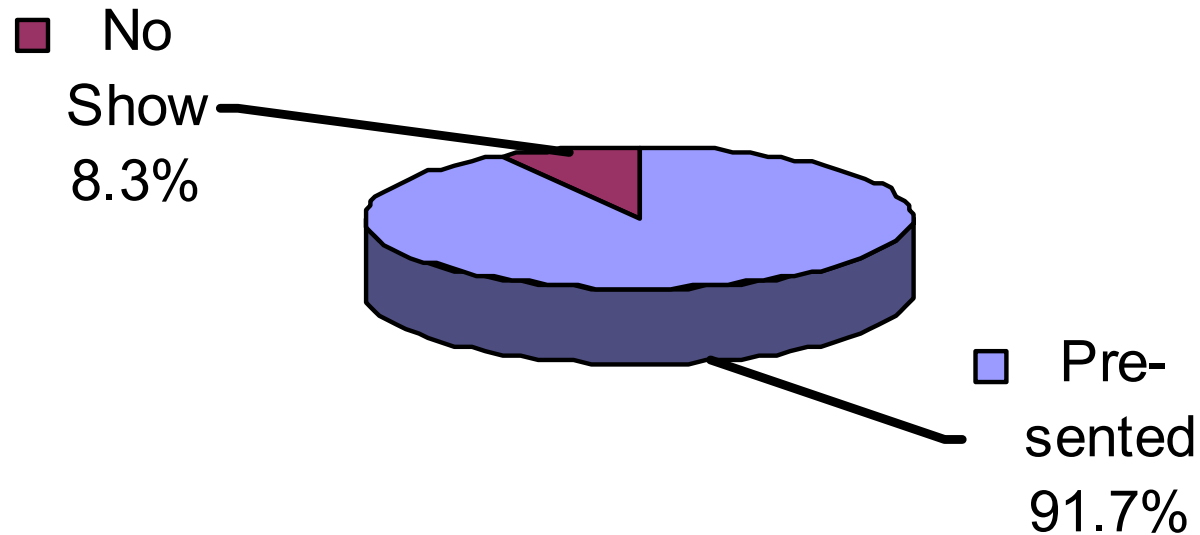
(2008 IEEE IUS, Beijing, China, November 2-5, 2008)



7. Presentations of accepted abstracts (674) in the conference

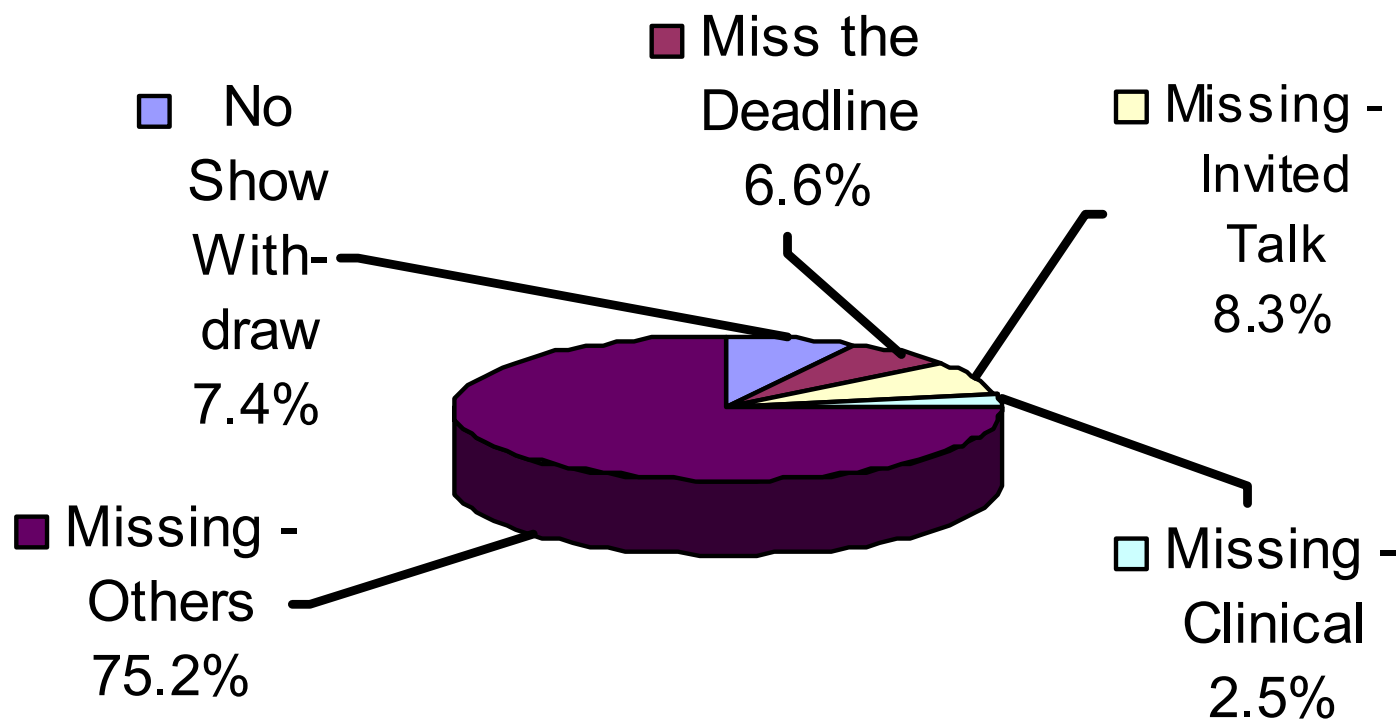
Abstract Presentation Statistics (Total 674 Abstracts)

(2008 IEEE IUS, Beijing, China, November 2-5, 2008)



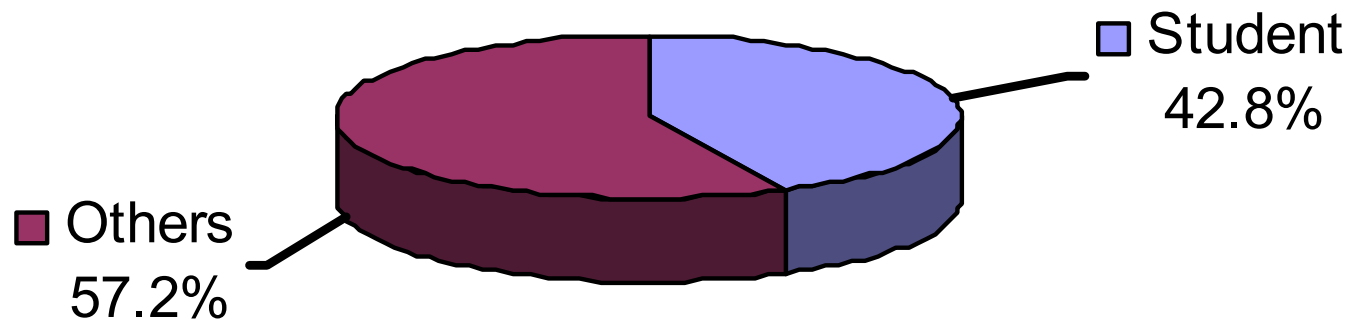
8. Categories of papers that are not published (121)

Papers Not in Proceedings (Total 121 Papers)
(2008 IEEE IUS, Beijing, China, November 2-5, 2008)

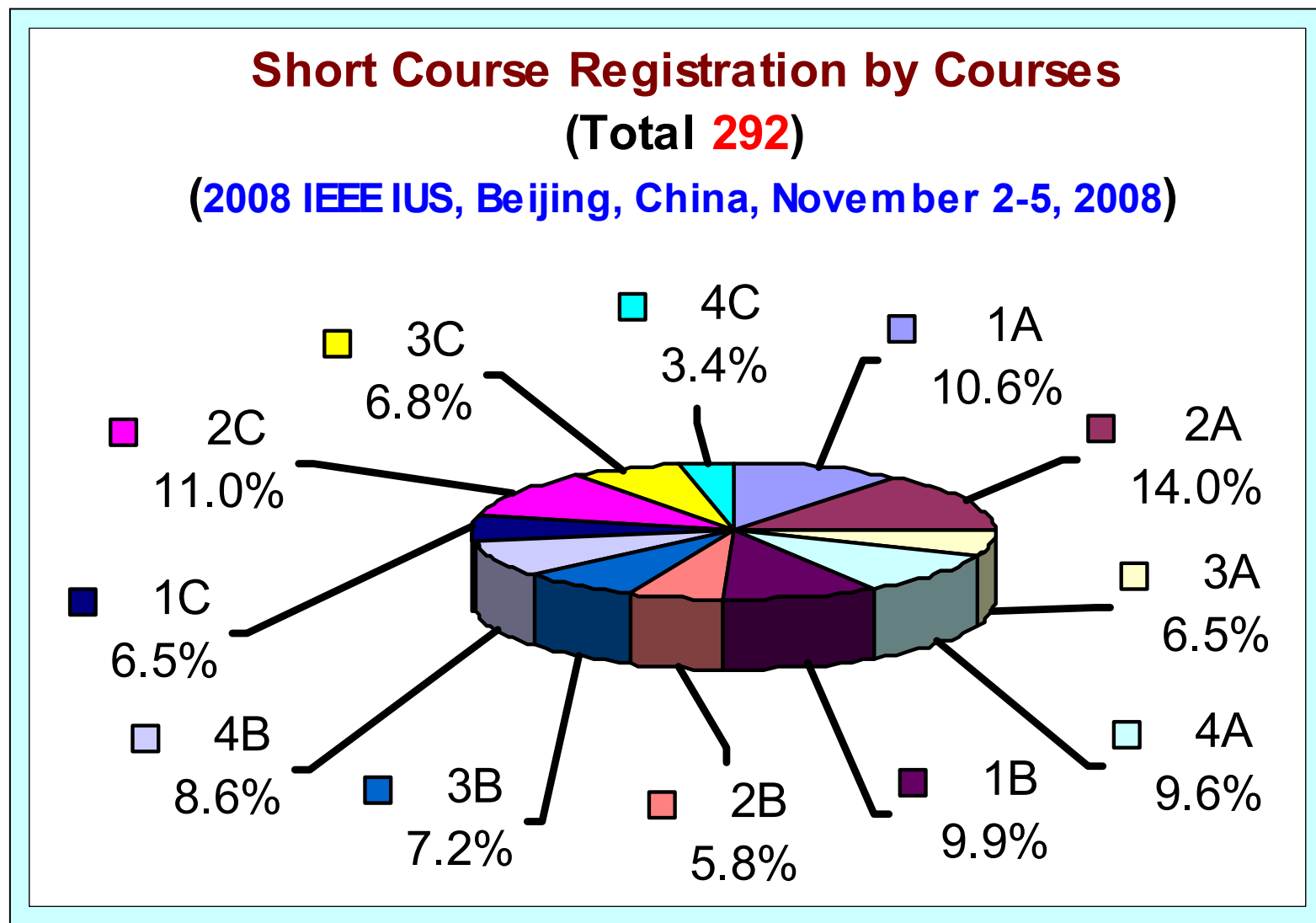


9. Short course registration (292) types

Short Course Registration Types (Total 292)
(2008 IEEE IUS, Beijing, China, November 2-5, 2008)



10. Attendances (total 292) of each of the 12 short courses



A list of the 12 short courses

- **8:00 A.M. - 12:00 Noon, Sunday, November 2, 2008:**
 - Short Course 1A** (Conference Room 311A/B): **Medical Ultrasound Transducers**, *Douglas G. Wildes* and *L. Scott Smith*, GE Global Research Center, Niskayuna, NY, USA.
 - Short Course 2A** (Conference Room 307): **Ultrasound Imaging Systems: from Principles to Implementation**, *Kai E. Thomenius*, GE Global Research Center, Niskayuna, NY, USA.
 - Short Course 3A** (Conference Room 308): **Photoacoustic Imaging and Sensing**, *Stanislav Emelianov*, Biomedical Engineering Department, University of Texas at Austin, USA.
 - Short Course 4A** (Conference Room 311C): **Estimation and Imaging of Tissue Motion and Blood Velocity**, *Hans Torp* and *Lasse Lovstakken*, Department of circulation and medical imaging, Norwegian University of Science and Technology, Trondheim, Norway.
- **1:00 P.M. - 5:00 P.M, Sunday, November 2, 2008:**
 - Short Course 1B** (Conference Room 311A/B): **Ultrasound Elastography: Quantitative Approaches**, **Jeffrey Bamber* and ***Paul Barbone*, **Institute of Cancer Research and Royal Marsden Hospital, UK. **Boston University, USA.*
 - Short Course 2B** (Conference Room 307): **Acoustic Microscopy - Fundamentals and Applications**, **Roman Gr. Maev*, ***Naohiro Hozumi*, ****Kazuto Kobayashi*, and *****Yoshifumi Saijo*, **Centre for Imaging Research and Advanced Materials Characterization, University of Windsor, Ontario, Canada. **Department of Electrical & Electronic Engineering, Aichi Institute of Technology, Toyota, Japan. ***Honda Electronics Co. Ltd., Aichi, Japan. ****Tohoku University, Sendai, Japan.*
 - Short Course 3B** (Conference Room 308): **Therapeutic Ultrasound**, *Lawrence A. Crum*, Applied Physics Laboratory, University of Washington, Seattle, WA, USA.
 - Short Course 4B** (Conference Room 311C): **SAW Modeling Techniques**, *Victor P. Plessky*, GVR Trade SA, Bevaix, Switzerland.
- **6:00 P.M. - 10:00 P.M, Sunday, November 2, 2008:**
 - Short Course 1C** (Conference Room 311A/B): **Ultrasound Contrast Agents: Theory and Experiment**, **Nico de Jong* and ***Michel Versluis*, **Erasmus MC, The Netherlands. **University of Twente, The Netherlands.*
 - Short Course 2C** (Conference Room 307): **CMUTs: Theory, Technology, and Applications**, *B.T. Khuri-Yakub*, *Ömer Oralkan*, and *Mario Kupnik*, E.L. Ginzton Laboratory, Stanford University, USA.
 - Short Course 3C** (Conference Room 308): **Time Reversal Acoustics**, *Mathias Fink*, École Supérieure de Physique et de Chimie de la Ville de Paris, France.
 - Short Course 4C** (Conference Room 311C): **Acoustical Near-Field Imaging**, *Walter Arnold*, Fraunhofer Institute for Non-Destructive Testing, Saarbrücken, Germany.